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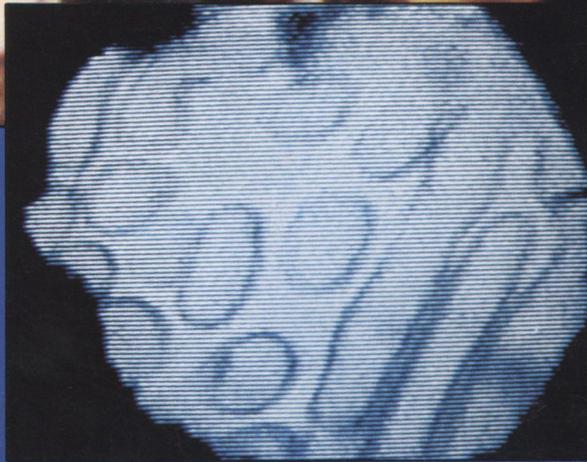
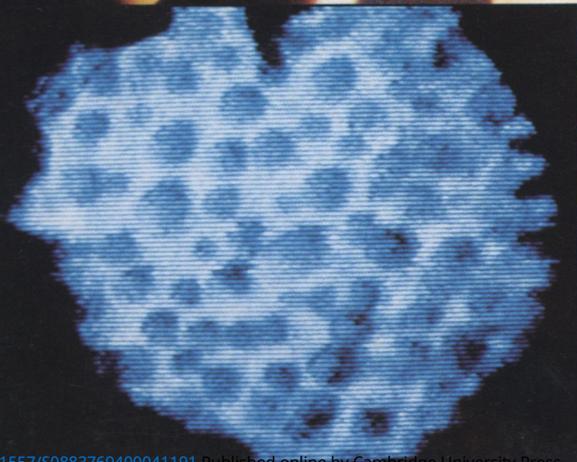
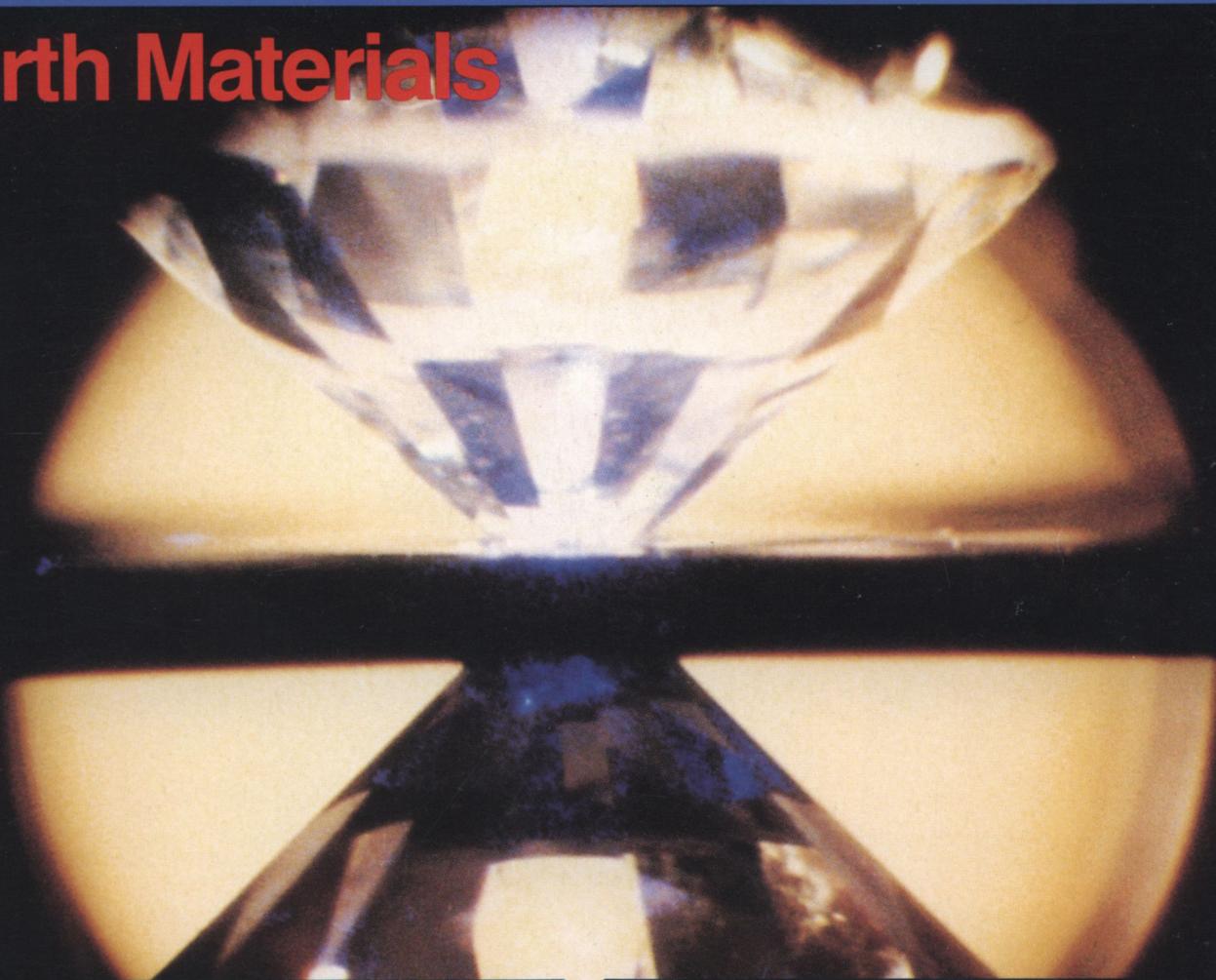
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May 1992, Volume XVII, No. 5



Earth Materials

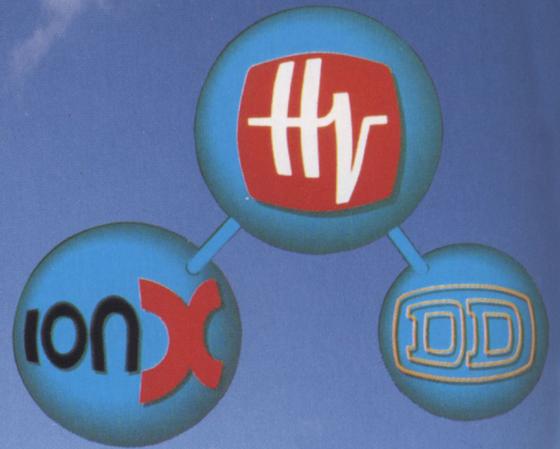


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EARTH MATERIALS

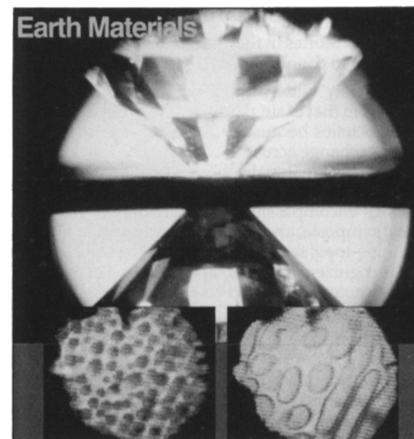
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ON THE COVER: Diamonds in a diamond-anvil cell press on a stainless steel gasket containing a small hole with a sample surrounded by a liquid pressure medium. The light-colored diamond is illuminated by a blue laser, but only a small amount of laser light passes through the gasket hole into the lower diamond. The bottom two video-camera images show hydrogen crystals nucleating from liquid hydrogen in a diamond-anvil cell at about 5 GPa (left). As the hydrogen crystals grow they become elongated (right). The horizontal lines are caused by the video camera. For more about high-pressure experimental methods, see "Materials Science of the Earth's Deep Interior" by A. Navrotsky et al. on p. 30.

About the Materials Research Society

The Materials Research Society (MRS), a nonprofit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 10,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and more than 40 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is an affiliate of the American Institute of Physics.

MRS publishes symposium proceedings, *MRS Bulletin*, *Journal of Materials Research*, and other publications related to current research activities.

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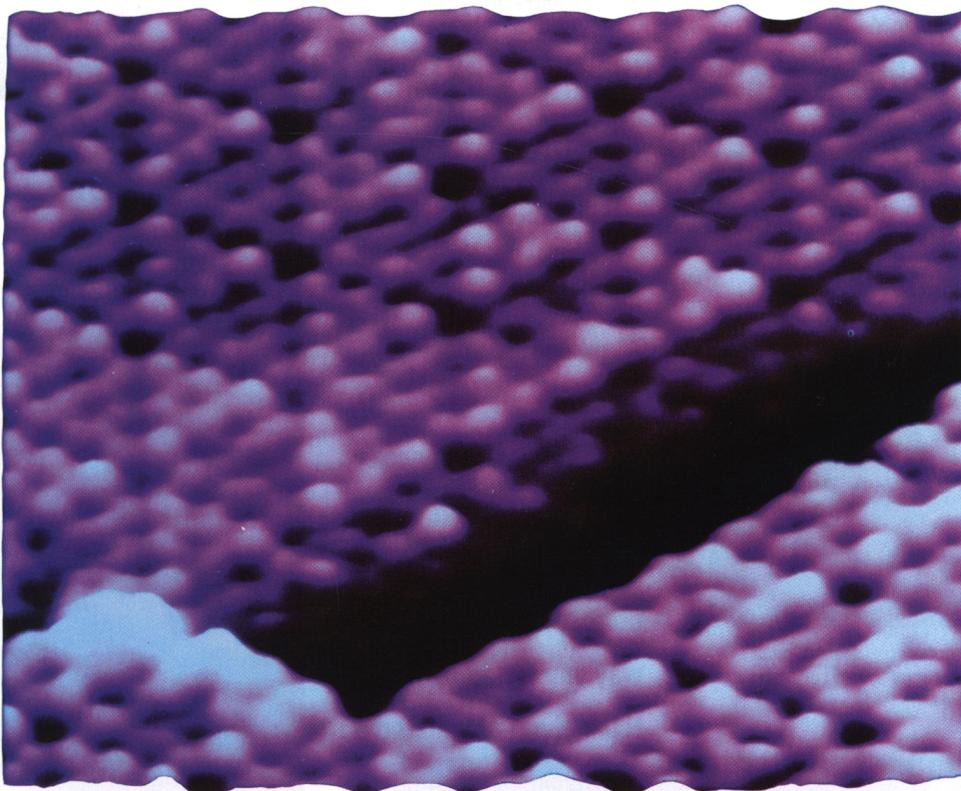
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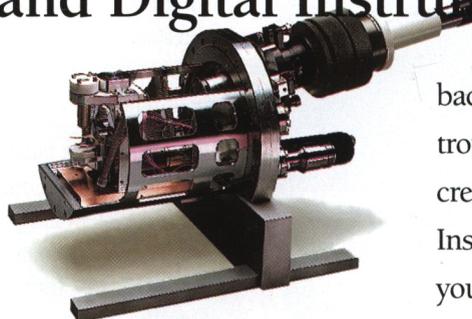
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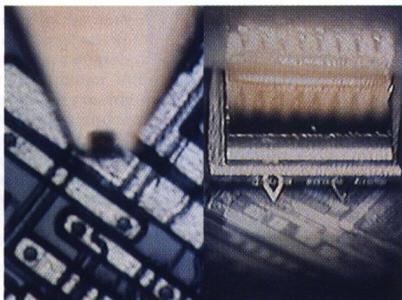
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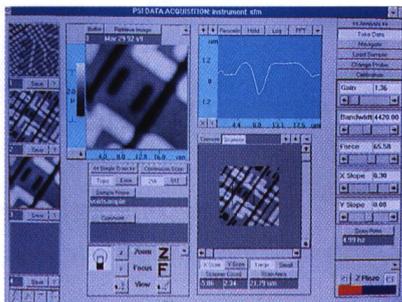
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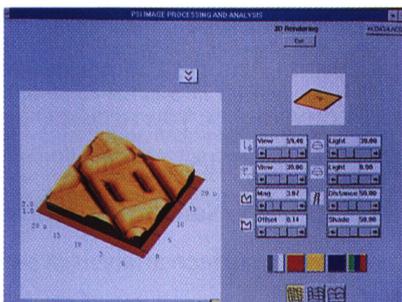
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